



# 8-CHANNEL, 12-/10-/8-BIT, 2.7-V TO 5.5-V LOW POWER DIGITAL-TO-ANALOG CONVERTER WITH POWER DOWN

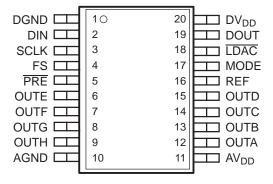
#### **FEATURES**

- Eight Voltage Output DACs in One Package
  - TLV5610 . . . 12-Bit
  - TLV5608 . . . 10-Bit
  - TLV5629 . . . 8-Bit
- Programmable Settling Time vs Power Consumption
  - 1 μs In Fast Mode
  - 3 μs In Slow Mode
- Compatible With TMS320 and SPI<sup>™</sup> Serial Ports
- Monotonic Over Temperature
- Low Power Consumption:
  - 18 mW In Slow Mode at 3-V
  - 48 mW In Fast Mode at 3-V
- Reference Input Buffers
- Power-Down Mode
- Buffered, High Impedance Reference Inputs
- Data Output for Daisy-Chaining

#### **APPLICATIONS**

- Digital Servo Control Loops
- Digital Offset and Gain Adjustment
- Industrial Process Control
- Machine and Motion Control Devices
- Mass Storage Devices

#### DW OR PW PACKAGE (TOP VIEW)



#### DESCRIPTION

The TLV5610, TLV5608, and TLV5629 are pin-compatible, eight-channel, 12-/10-/8-bit voltage output DACs each with a flexible serial interface. The serial interface allows glueless interface to TMS320 and SPI, QSPI, and Microwire serial ports. It is programmed with a 16-bit serial string containing 4 control and 12 data bits.

Additional features are a power-down mode, an LDAC input for simultaneous update of all eight DAC outputs, and a data output which can be used to cascade multiple devices.

The resistor string output voltage is buffered by a rail-to-rail output amplifier with a programmable settling time to allow the designer to optimize speed vs power dissipation. The buffered, high-impedance reference input can be connected to the supply voltage.

Implemented with a CMOS process, the DACs are designed for single-supply operation from 2.7 V to 5.5 V, and can operate on two separate analog and digital power supplies. The devices are available in 20-pin SOIC and TSSOP packages.

## **AVAILABLE OPTIONS**

т		PACKAGE								
$T_A$	SMALL OUTLINE (DW)	TSSOP (PW)	RESOLUTION							
	TLV5610IDW	TLV5610IPW	12							
-40°C to 85°C	TLV5608IDW	TLV5608IPW	10							
	TLV5629IDW	TLV5629IPW	8							

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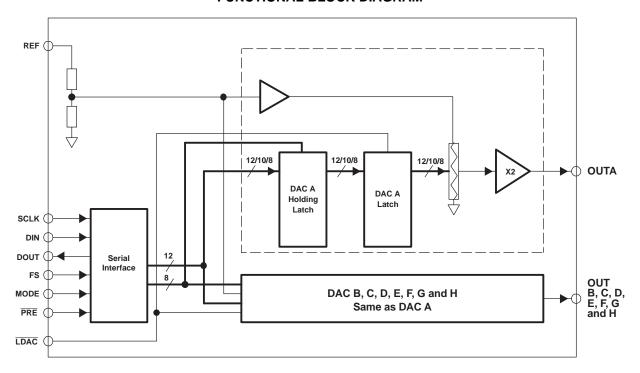
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These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

## **FUNCTIONAL BLOCK DIAGRAM**



## **Terminal Functions**

TERM	IINAL	I/O	DESCRIPTION
NAME	NO.	1/0	DESCRIPTION
AGND	10	I	Analog ground
$AV_{DD}$	11	I	Analog power supply
DGND	1	I	Digital ground
DIN	2	I	Digital serial data input
DOUT	19	0	Digital serial data output
$DV_DD$	20	I	Digital power supply
FS	4	I	Frame sync input
LDAC	18	I	Load DAC. The DAC outputs are only updated, if this signal is low. It is an asynchronous input.
MODE	17	I	DSP/ $\mu$ C mode pin. High = $\mu$ C mode, NC = DSP mode.
PRE	5	I	Preset input
REF	16	I	Voltage reference input
SCLK	3	I	Serial clock input
OUTA-OUTH	6-9, 12-15	0	DAC outputs A, B, C, D, E, F, G and H



## **ABSOLUTE MAXIMUM RATINGS**

over operating free-air temperature range (unless otherwise noted)(1)

	UNIT
Supply voltage (AV <sub>DD</sub> , DV <sub>DD</sub> to GND)	7 V
Reference input voltage	- 0.3 V to AV <sub>DD</sub> + 0.3 V
Digital input voltage range	- 0.3 V to DV <sub>DD</sub> + 0.3 V
Operating free-air temperature range, T <sub>A</sub>	-40°C to 85°C
Storage temperature range, T <sub>stg</sub>	-65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C

<sup>(1)</sup> Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under recommended operating conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

#### RECOMMENDED OPERATING CONDITIONS

		MIN	NOM	MAX	UNIT
Supply voltage, AV <sub>DD</sub> , DV <sub>DD</sub>	5-V operation	4.5	5	5.5	V
	3-V operation	2.7	3	3.3	V
High level digital input valtage V	DV <sub>DD</sub> = 2.7 V	2			V
High-level digital input voltage, V <sub>IH</sub>	DV <sub>DD</sub> = 5.5 V	2.4			V
Low lovel digital ignut valtage. V	DV <sub>DD</sub> = 2.7 V			0.6	V
Low-level digital input voltage, V <sub>IL</sub>	DV <sub>DD</sub> = 5.5 V			1	V
Reference voltage, V <sub>ref</sub>	AV <sub>DD</sub> = 5 V	GND	4.096	$AV_{DD}$	V
	$AV_{DD} = 3 V$	GND	2.048	$AV_{DD}$	V
Load resistance, R <sub>L</sub>		2			kΩ
Load capacitance, C <sub>L</sub>				100	pF
Clock frequency, f <sub>CLK</sub>				30	MHz
Operating free-air temperature, T <sub>A</sub>		-40		85	°C

#### **ELECTRICAL CHARACTERISTICS**

over recommended operating free-air temperature range, supply voltages, and reference voltages (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
POWER	R SUPPLY						
	Power cumply current		No load, V <sub>ref</sub> = 4.096 V, See <sup>(1)</sup>		16	21	mΛ
I <sub>DD</sub>	Power supply current	Slow	All inputs = $DV_{DD}$ or GND		6	8	mA
	Power down supply current				0.1		μΑ
POR	Power on threshold				2		V
PSRR	Power supply rejection ratio	ı	Full scale, See (2)		-60		dB

 $I_{DD}$  is measured while continuously writing code 2048 to the DAC. For  $V_{IH} < DV_{DD}$  - 0.7 V and  $V_{IL} > 0.7$  V, supply current increases. Power supply rejection ratio at full scale is measured by varying  $AV_{DD}$  and is given by:  $PSRR = 20 log [(E_G(AV_{DD}max) - E_G(AV_{DD}min))/V_{DD}max]$ 



## **ELECTRICAL CHARACTERISTICS (continued)**

over recommended operating free-air temperature range, supply voltages, and reference voltages (unless otherwise noted)

	PARAMETER		TEST	CONDITIONS	MIN	TYP	MAX	UNIT
STATIC	DAC SPECIFICATIONS							
		TLV5610				12		
	Resolution	TLV5608				10		Bits
		TLV5629				8		
		TLV5610		Code 40 to 4095		±2	±6	
	Integral nonlinearity (INL)	TLV5608	V <sub>ref</sub> = 2 V, 4V	Code 20 to 1023		±0.5	±2	LSB
		TLV5629		Code 6 to 255		±0.3	±1	
		TLV5610		Code 40 to 4095		±0.5	±1	
	Differential nonlinearity (DNL)	TLV5608	V <sub>ref</sub> = 2 V, 4V	Code 20 to 1023		±0.1	±1	LSB
		TLV5629		Code 6 to 255		±0.1	±1	
Ezs	Zero-scale error (offset error at	zero scale)		·			±30	mV
E <sub>ZS</sub> TC	Zero-scale-error temperature co	pefficient				30		μV/°C
E <sub>G</sub>	Gain error						±0.6	% of FS voltage
E <sub>G</sub> TC	Gain error temperature coefficie	ent				10		ppm/°C
OUTPU	T SPECIFICATIONS							
Vo	Voltage output range		R <sub>L</sub> = 10 kΩ		0		AV <sub>DD</sub> - 0.4	V
	Output load regulation accuracy	y	$R_L = 2 k\Omega \text{ vs } 10 \text{ l}$	kΩ			±0.3	% of FS voltage
REFERE	ENCE INPUT							
VI	Reference input voltage				0		$AV_{DD}$	V
R <sub>I</sub>	Reference input resistance					100		kΩ
Cı	Reference input capacitance					5		pF
	Defense in south and width	Fast	$V_{ref} = 0.4 V_{pp} + 2$ Input code = 0x8	048 Vdc, 00		2.2		N/I I-
	Reference input bandwidth	Slow	$V_{ref} = 2 V_{pp} \text{ at 1 I}$ See (3)	KHz + 2.048 Vdc,		1.9		MHz
	Reference feedthrough					-84		dB
DIGITAL	_ INPUT		•					
I <sub>IH</sub>	High-level digital input current		$V_I = V_{DD}$				1	μΑ
I <sub>IL</sub>	Low-level digital input current		$V_I = 0 V$		-1			μΑ
C <sub>I</sub>	Input capacitance					8		pF
DIGITAL	_ OUTPUT						,	
$V_{OH}$	High-level digital output voltage	)	$R_L = 10 \text{ k}\Omega$		2.6			V
$V_{OL}$	Low-level digital output voltage		$R_L = 10 \text{ k}\Omega$			0.4	V	
	Output voltage rise time		$R_L = 10 \text{ k}\Omega, C_L = $ propagation dela			7	20	ns

<sup>(3)</sup> Reference feedthrough is measured at the DAC output with an input code = 0x000.



## **ELECTRICAL CHARACTERISTICS (continued)**

over recommended operating free-air temperature range, supply voltages, and reference voltages (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT			
ANALO	NALOG OUTPUT DYNAMIC PERFORMANCE									
+	Output pottling time (full people)	Fast	$R_L = 10 \text{ k}\Omega, C_L = 100 \text{ pF, See}^{(4)}$		1	3				
t <sub>s(FS)</sub>	Output settling time (full scale)	Slow	R <sub>L</sub> = 10 kΩ, C <sub>L</sub> = 100 pr, See · ·		3	7	μs			
+	Output settling time, code to	butput settling time, code to $R_L = 10 \text{ k}\Omega$ , $C_L = 100 \text{ pF}$ , See $R_L = 10 \text{ k}\Omega$			0.5	1				
I-(00)	code	Slow	$R_L = 10 \text{ k}\Omega$ , $G_L = 100 \text{ pr}$ , See $\odot$		1	2	μs			
CD	Claw rate	Fast	$R_L = 10 \text{ k}\Omega$ , $C_L = 100 \text{ pF}$ , See <sup>(6)</sup>	4	10		1//			
SR	Slew rate	Slow	$-R_L = 10 \text{ k}\Omega$ , $C_L = 100 \text{ pr}$ , See $\sim$	1	3		V/μs			
	Glitch energy	•	See (7)		4		nV-s			
	Channel crosstalk		10 kHz sine, 4 V <sub>PP</sub>		-90		dB			

<sup>(4)</sup> Settling time is the time for the output signal to remain within +0.5 LSB of the final measured value for a digital input code change of 0x80 to 0xFFF and 0xFFF to 0x080, respectively. Assured by design; not tested.

## **TIMING REQUIREMENTS**

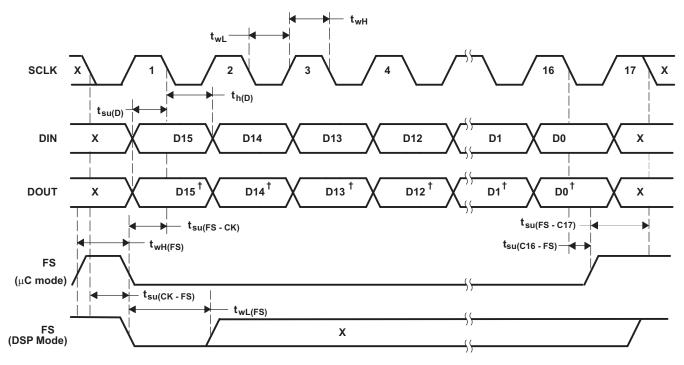
DIGITAL INI	PUTS				
		MIN	NOM	MAX	UNIT
t <sub>su(FS-CK)</sub>	Setup time, FS low before next negative SCLK edge	8			ns
t <sub>su(C16-FS)</sub>	Setup time, 16 <sup>th</sup> negative edge after FS low on which bit D0 is sampled before rising edge of FS. μC mode only	10			ns
t <sub>su(FS-C17)</sub>	μC mode, setup time, FS high before 17 <sup>th</sup> negative edge of SCLK.	10			ns
t <sub>su(CK-FS)</sub>	DSP mode, setup time, SLCK low before FS low.	5			ns
t <sub>wL(LDAC)</sub>	LDAC duration low	10			ns
t <sub>wH</sub>	SCLK pulse duration high	16			ns
t <sub>wL</sub>	SCLK pulse duration low	16			ns
t <sub>su(D)</sub>	Setup time, data ready before SCLK falling edge	8			ns
t <sub>h(D)</sub>	Hold time, data held valid after SCLK falling edge	5			ns
t <sub>wH(FS)</sub>	FS duration high	10			ns
t <sub>wL(FS)</sub>	FS duration low	10			ns
t <sub>s</sub>	Settling time	See AC specs			

<sup>(5)</sup> Settling time is the time for the output signal to remain within +0.5 LSB of the final measured value for a digital input code change of one count. The max time applies to code changes near zero scale or full scale. Assured by design; not tested.

<sup>(6)</sup> Slew rate determines the time it takes for a change of the DAC output from 10% to 90% full scale voltage.

<sup>(7)</sup> Code transition: TLV5610 - 0x7FF to 0x800, TLV5608 - 0x7FC to 0x800, TLV5629 - 0x7F0 to 0x800

## PARAMETER MEASUREMENT INFORMATION



<sup>†</sup> Previous input data

**Figure 1. Serial Interface Timing** 

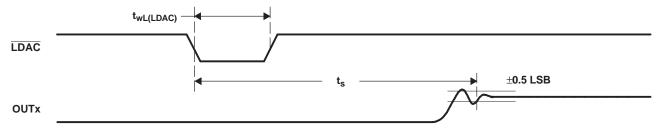
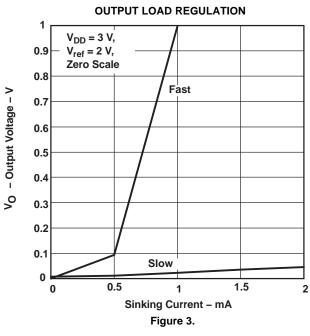
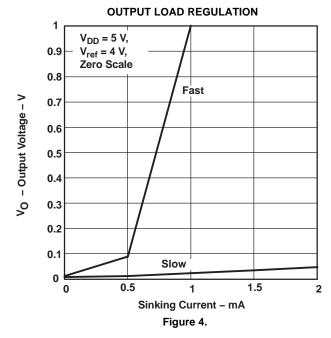


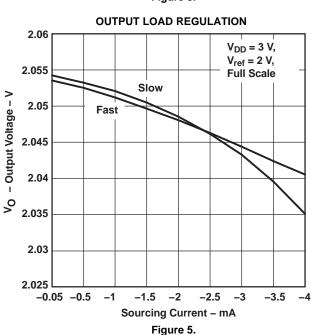
Figure 2. Output Timing

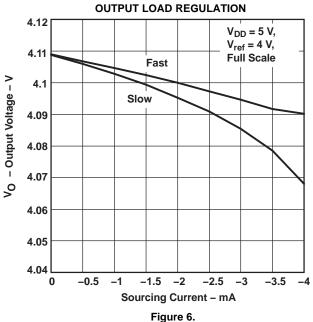


## TYPICAL CHARACTERISTICS





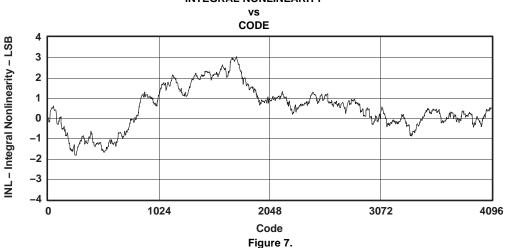




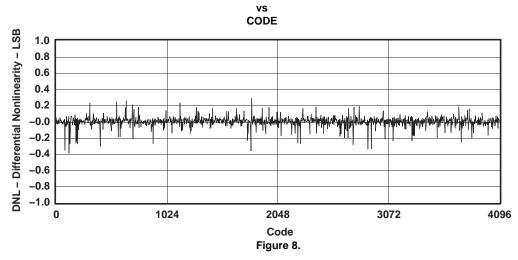


## **TYPICAL CHARACTERISTICS (continued)**

## TLV5610 INTEGRAL NONLINEARITY



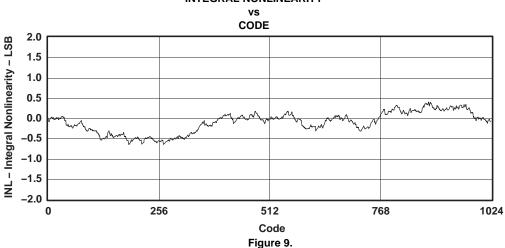
## TLV5610 DIFFERENTIAL NONLINEARITY



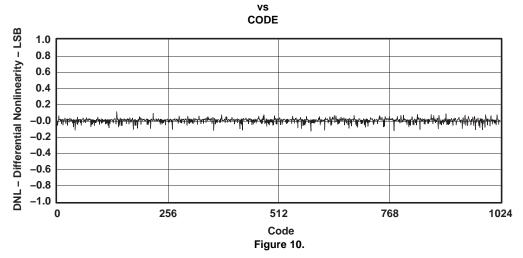


## **TYPICAL CHARACTERISTICS (continued)**

## TLV5608 INTEGRAL NONLINEARITY



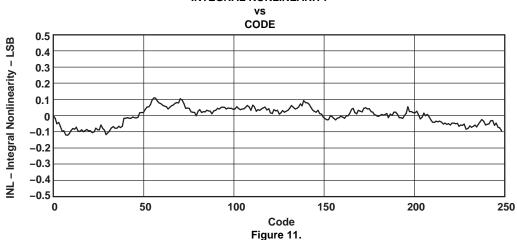
## TLV5608 DIFFERENTIAL NONLINEARITY



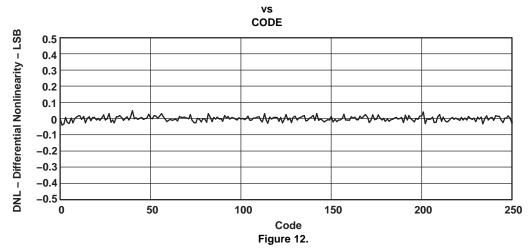


## **TYPICAL CHARACTERISTICS (continued)**

## TLV5629 INTEGRAL NONLINEARITY



## TLV5629 DIFFERENTIAL NONLINEARITY





## **APPLICATION INFORMATION**

#### **GENERAL FUNCTION**

The TLV5610, TLV5608, and TLV5629 are 8-channel, 12-bit, single-supply DACs, based on a resistor string architecture. They consist of a serial interface, a speed and power-down control logic, a reference input buffer, a resistor string, and a rail-to-rail output buffer.

The output voltage (full scale determined by external reference) for each channel is given by:

$$REF \frac{CODE}{0x1000} [V]$$
 (1)

where REF is the reference voltage and CODE is the digital input value. The input range is 0x000 to 0xFFF for the TLV5610, 0x000 to 0xFFC for the TLV5608, and 0x000 to 0xFF0 for the TLV5629.

## **POWER ON RESET (POR)**

The built-in power-on-reset circuit controls the output voltage after power up. On <u>power</u> up, all latches including the preset register are set to zero, but the DAC outputs are only set to zero if the <u>LDAC</u> is low. The DAC outputs may have a small offset error produced by the output buffer. The registers remains at zero until a valid write sequence is made to the DAC, changing the DAC register data. This is useful in applications where it is important to know the state of the outputs of the DAC after power up. All digital inputs must be logic low until the digital and analog supplies are applied. Any logic high voltages applied to the logic input pins when power is not applied to  $AV_{DD}$  and  $DV_{DD}$ , may power the device logic circuit through the overvoltage protection diode causing an undesired operation. When separate analog  $AV_{DD}$  and digital  $DV_{DD}$  supplies are used,  $AV_{DD}$  must come up first before  $DV_{DD}$ , to ensure that the power-on-reset circuit operates correctly.

## **SERIAL INTERFACE**

A falling edge of FS starts shifting the data on DIN starting with the MSB to the internal register on the falling edges of SCLK. After 16 bits have been transferred, the content of the shift register is moved to one of the DAC holding registers, depending on the address bits within the data word. A logic 0 on the LDAC pin is required to transfer the content of the DAC holding register to the DAC latch and to update the DAC outputs. LDAC is an asynchronous input. It can be held low if a simultaneous update of all eight channels is not needed.

For daisy-chaining, DOUT provides the data sampled on DIN with a delay of 16 clock cycles.

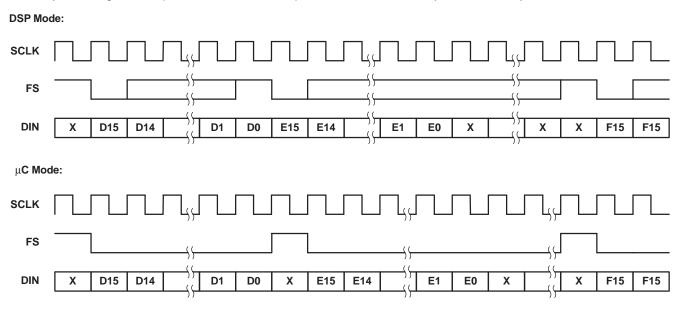


Figure 13. Data Sampled on DIN



Difference between DSP mode (MODE = N.C. or 0) and  $\mu$ C (MODE = 1) mode:

- In μC mode, FS needs to be held low until all 16 data bits have been transferred. If FS is driven high before the 16th falling clock edge, the data transfer is cancelled. The DAC is updated after a rising edge on FS.
- In DSP mode, FS needs to stay low for 20 ns and can go high before the 16th falling clock edge.
- In DSP mode there needs to be one falling SCLK edge before FS goes low to start the write (DIN) cycle. This
  extra falling SCLK edge has to happen at least 5 ns before FS goes low, t<sub>su(CK-FS)</sub> ≥ 5 ns.
- In μC mode, the extra falling SCLK edge is not necessary. However, if it does happen, the extra negative SCLK edge is not allowed to occur within 10 ns after FS goes HIGH to finish the WRITE cycle (t<sub>su(FS-C17)</sub>).

#### SERIAL CLOCK FREQUENCY AND UPDATE RATE

The maximum serial clock frequency is given by:

$$f_{\text{sclkmax}} = \frac{1}{t_{\text{whmin}} + t_{\text{wlmin}}} = 30 \text{ MHz}$$
(2)

The maximum update rate is:

$$f_{\text{updatemax}} = \frac{1}{16 \left( t_{\text{whmin}} + t_{\text{wlmin}} \right)} = 1.95 \text{ MHz}$$
(3)

Note, that the maximum update rate is just a theoretical value for the serial interface, as the settling time of the DAC has to be considered also.

#### **DATA FORMAT**

The 16-bit data word consists of two parts:

- Address bits (D150D12)
- Data bits (D110D0)

D15	D14	D13	D12	D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
А3	A2	A1	Α0		DATA										

#### **Register Map**

A3	A2	A1	A0	FUNCTION
0	0	0	0	DAC A
0	0	0	1	DAC B
0	0	1	0	DAC C
0	0	1	1	DAC D
0	1	0	0	DAC E
0	1	0	1	DAC F
0	1	1	0	DAC G
0	1	1	1	DAC H
1	0	0	0	CTRL0
1	0	0	1	CTRL1
1	0	1	0	Preset
1	0	1	1	Reserved
1	1	0	0	DAC A and B
1	1	0	1	DAC C and $\overline{D}$
1	1	1	0	DAC E and F
1	1	1	1	DAC G and H



#### DAC A-H AND TWO-CHANNEL REGISTERS

Writing to DAC A-H sets the output voltage of channel A-H. It is possible to automatically generate the complement of one channel by writing to one of the four two-channel registers (DAC A and B etc.).

The TLV5610 decodes all 12 data bits. The TLV5608 decodes D11 to D2 (D1 and D0 are ignored). The TLV5629 decodes D11 to D4 (D3 to D0 are ignored).

## **PRESET**

The outputs of the DAC channels can be driven simultaneously to a predefined value stored in the preset register by driving the PRE input pin low and asserting the LDAC input pin. The preset register is cleared (set to zero) by the POR circuit after power up. Therefore, it must be written with a predefined value before asserting the PRE pin low, unless zero is the desired preset value. The PRE input is asynchronous to the clock.

## CTRL0

D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
Х	Х	Х	Х	Х	Х	Х	PD	DO	Х	Х	IM

PD : Full device power down 0 = normal 1 = power down

DO : Digital output enable 0 = disable 1 = enable

IM : Input mode 0 = straight binary 1 = twos complement

X : Reserved

If DOUT is enabled, the data input on DIN is output on DOUT with a 16-cycle delay. That makes it possible to daisy-chain multiple DACs on one serial bus.

## CTRL1

D11	D10	D9	D8	D7	D6	D5	D4	D3	D2	D1	D0
Х	X	X	X	$P_{GH}$	P <sub>EF</sub>	$P_{CD}$	$P_{AB}$	S <sub>GH</sub>	S <sub>EF</sub>	S <sub>CD</sub>	S <sub>AB</sub>

 $P_{XY}$ : Power down DAC<sub>XY</sub> 0 = normal 1 = power down

 $S_{xy}$ : Speed DAC<sub>xy</sub> 0 = slow 1 = fast

XY : DAC pair AB, CD, EF, or GH

In power-down mode, the amplifiers of the selected DAC pair within the device are disabled and the total power consumption of the device is significantly reduced. Power-down mode of a specific DAC pair can be selected by setting the PXY bit within the data word to 1.

There are two settling time modes: fast and slow. Fast mode of a DAC pair is selected by setting  $S_{XY}$  to 1 and slow mode is selected by setting  $S_{XY}$  to 0.

## REFERENCE

The DAC reference can be sourced externally using precision reference circuits. Since the reference input is buffered, it can be connected to the supply voltage.

#### **BUFFERED AMPLIFIER**

The DAC outputs are buffered by an amplifier with a gain of two, which are configurable as Class A (fast mode) or Class AB (slow or low-power mode). The output buffers have near rail-to-rail output with short-circuit protection, and can reliably drive a  $2-k\Omega$  load with a 100-pF load capacitance.

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## **PACKAGING INFORMATION**

Orderable part number	Status (1)	Material type	Package   Pins	Package qty   Carrier	<b>RoHS</b> (3)	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
TLV5608IDW	Active	Production	SOIC (DW)   20	25   TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TLV5608I
TLV5608IDW.B	Active	Production	SOIC (DW)   20	25   TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TLV5608I
TLV5608IDWG4	Active	Production	SOIC (DW)   20	25   TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TLV5608I
TLV5608IDWG4.B	Active	Production	SOIC (DW)   20	25   TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TLV5608I
TLV5608IDWR	Active	Production	SOIC (DW)   20	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TLV5608I
TLV5608IDWR.B	Active	Production	SOIC (DW)   20	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TLV5608I
TLV5608IPW	Active	Production	TSSOP (PW)   20	70   TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TY5608
TLV5608IPW.B	Active	Production	TSSOP (PW)   20	70   TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TY5608
TLV5608IPWG4	Active	Production	TSSOP (PW)   20	70   TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TY5608
TLV5608IPWG4.B	Active	Production	TSSOP (PW)   20	70   TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TY5608
TLV5608IPWR	Active	Production	TSSOP (PW)   20	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TY5608
TLV5608IPWR.B	Active	Production	TSSOP (PW)   20	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TY5608
TLV5608IPWRG4	Active	Production	TSSOP (PW)   20	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TY5608
TLV5610IDW	Active	Production	SOIC (DW)   20	25   TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TLV5610I
TLV5610IDW.B	Active	Production	SOIC (DW)   20	25   TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TLV5610I
TLV5610IDWR	Active	Production	SOIC (DW)   20	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TLV5610I
TLV5610IDWR.B	Active	Production	SOIC (DW)   20	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TLV5610I
TLV5610IDWRG4	Active	Production	SOIC (DW)   20	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TLV5610I
TLV5610IDWRG4.B	Active	Production	SOIC (DW)   20	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TLV5610I
TLV5610IPW	Active	Production	TSSOP (PW)   20	70   TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TY5610
TLV5610IPW.B	Active	Production	TSSOP (PW)   20	70   TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TY5610
TLV5610IPWG4	Active	Production	TSSOP (PW)   20	70   TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TY5610
TLV5610IPWG4.B	Active	Production	TSSOP (PW)   20	70   TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TY5610
TLV5610IPWR	Active	Production	TSSOP (PW)   20	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TY5610
TLV5610IPWR.B	Active	Production	TSSOP (PW)   20	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TY5610
TLV5629IDW	Active	Production	SOIC (DW)   20	25   TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TLV5629I
TLV5629IDW.B	Active	Production	SOIC (DW)   20	25   TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TLV5629I
TLV5629IDWG4	Active	Production	SOIC (DW)   20	25   TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TLV5629I
TLV5629IDWR	Active	Production	SOIC (DW)   20	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TLV5629I





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Orderable part number	Status	Material type	Package   Pins	Package qty   Carrier	RoHS	Lead finish/ Ball material	MSL rating/ Peak reflow	Op temp (°C)	Part marking (6)
	( )	( )			(-)	(4)	(5)		(-)
TLV5629IDWR.B	Active	Production	SOIC (DW)   20	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TLV5629I
TLV5629IPW	Active	Production	TSSOP (PW)   20	70   TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TY5629
TLV5629IPW.B	Active	Production	TSSOP (PW)   20	70   TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TY5629
TLV5629IPWG4	Active	Production	TSSOP (PW)   20	70   TUBE	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TY5629
TLV5629IPWR	Active	Production	TSSOP (PW)   20	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TY5629
TLV5629IPWR.B	Active	Production	TSSOP (PW)   20	2000   LARGE T&R	Yes	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TY5629

<sup>(1)</sup> Status: For more details on status, see our product life cycle.

Multiple part markings will be inside parentheses. Only one part marking contained in parentheses and separated by a "~" will appear on a part. If a line is indented then it is a continuation of the previous line and the two combined represent the entire part marking for that device.

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<sup>(3)</sup> RoHS values: Yes, No. RoHS Exempt. See the TI RoHS Statement for additional information and value definition.

<sup>(4)</sup> Lead finish/Ball material: Parts may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

<sup>(5)</sup> MSL rating/Peak reflow: The moisture sensitivity level ratings and peak solder (reflow) temperatures. In the event that a part has multiple moisture sensitivity ratings, only the lowest level per JEDEC standards is shown. Refer to the shipping label for the actual reflow temperature that will be used to mount the part to the printed circuit board.

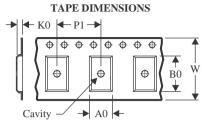
<sup>(6)</sup> Part marking: There may be an additional marking, which relates to the logo, the lot trace code information, or the environmental category of the part.

## **PACKAGE MATERIALS INFORMATION**

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## TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

## QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TLV5608IDWR	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1
TLV5608IPWR	TSSOP	PW	20	2000	330.0	16.4	6.95	7.1	1.6	8.0	16.0	Q1
TLV5610IDWR	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1
TLV5610IDWRG4	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1
TLV5610IPWR	TSSOP	PW	20	2000	330.0	16.4	6.95	7.1	1.6	8.0	16.0	Q1
TLV5629IDWR	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1
TLV5629IPWR	TSSOP	PW	20	2000	330.0	16.4	6.95	7.1	1.6	8.0	16.0	Q1



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\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TLV5608IDWR	SOIC	DW	20	2000	350.0	350.0	43.0
TLV5608IPWR	TSSOP	PW	20	2000	350.0	350.0	43.0
TLV5610IDWR	SOIC	DW	20	2000	350.0	350.0	43.0
TLV5610IDWRG4	SOIC	DW	20	2000	350.0	350.0	43.0
TLV5610IPWR	TSSOP	PW	20	2000	350.0	350.0	43.0
TLV5629IDWR	SOIC	DW	20	2000	350.0	350.0	43.0
TLV5629IPWR	TSSOP	PW	20	2000	350.0	350.0	43.0



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## **TUBE**

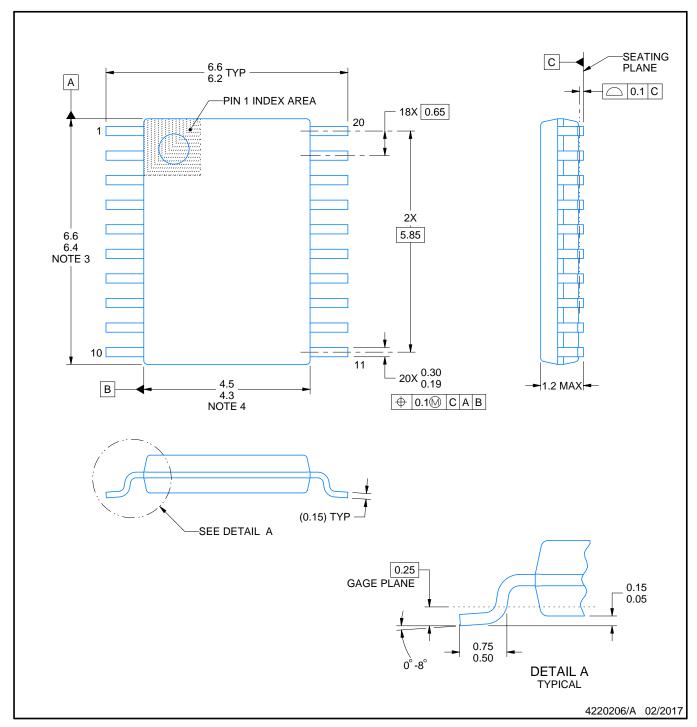


\*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (µm)	B (mm)
TLV5608IDW	DW	SOIC	20	25	506.98	12.7	4826	6.6
TLV5608IDW.B	DW	SOIC	20	25	506.98	12.7	4826	6.6
TLV5608IDWG4	DW	SOIC	20	25	506.98	12.7	4826	6.6
TLV5608IDWG4.B	DW	SOIC	20	25	506.98	12.7	4826	6.6
TLV5608IPW	PW	TSSOP	20	70	530	10.2	3600	3.5
TLV5608IPW.B	PW	TSSOP	20	70	530	10.2	3600	3.5
TLV5608IPWG4	PW	TSSOP	20	70	530	10.2	3600	3.5
TLV5608IPWG4.B	PW	TSSOP	20	70	530	10.2	3600	3.5
TLV5610IDW	DW	SOIC	20	25	506.98	12.7	4826	6.6
TLV5610IDW.B	DW	SOIC	20	25	506.98	12.7	4826	6.6
TLV5610IPW	PW	TSSOP	20	70	530	10.2	3600	3.5
TLV5610IPW.B	PW	TSSOP	20	70	530	10.2	3600	3.5
TLV5610IPWG4	PW	TSSOP	20	70	530	10.2	3600	3.5
TLV5610IPWG4.B	PW	TSSOP	20	70	530	10.2	3600	3.5
TLV5629IDW	DW	SOIC	20	25	506.98	12.7	4826	6.6
TLV5629IDW.B	DW	SOIC	20	25	506.98	12.7	4826	6.6
TLV5629IDWG4	DW	SOIC	20	25	506.98	12.7	4826	6.6
TLV5629IPW	PW	TSSOP	20	70	530	10.2	3600	3.5
TLV5629IPW.B	PW	TSSOP	20	70	530	10.2	3600	3.5
TLV5629IPWG4	PW	TSSOP	20	70	530	10.2	3600	3.5



SMALL OUTLINE PACKAGE



## NOTES:

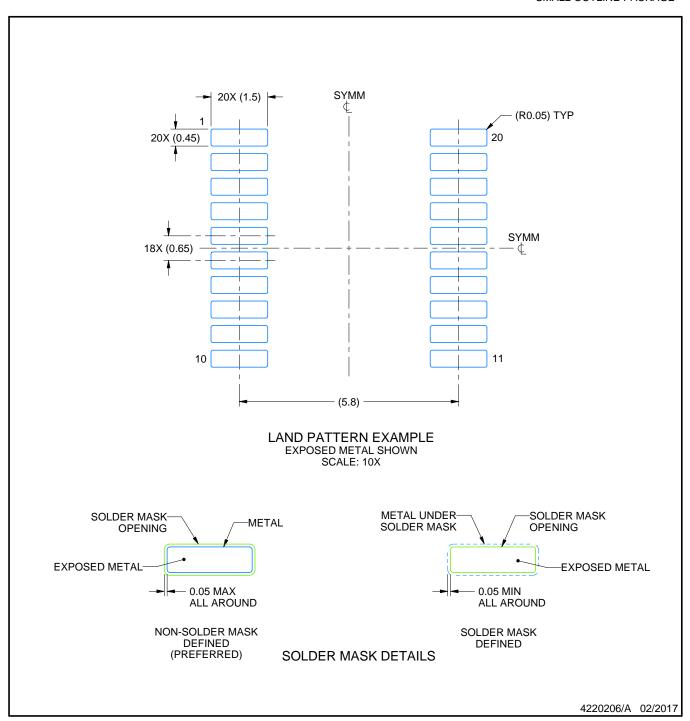
- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



SMALL OUTLINE PACKAGE



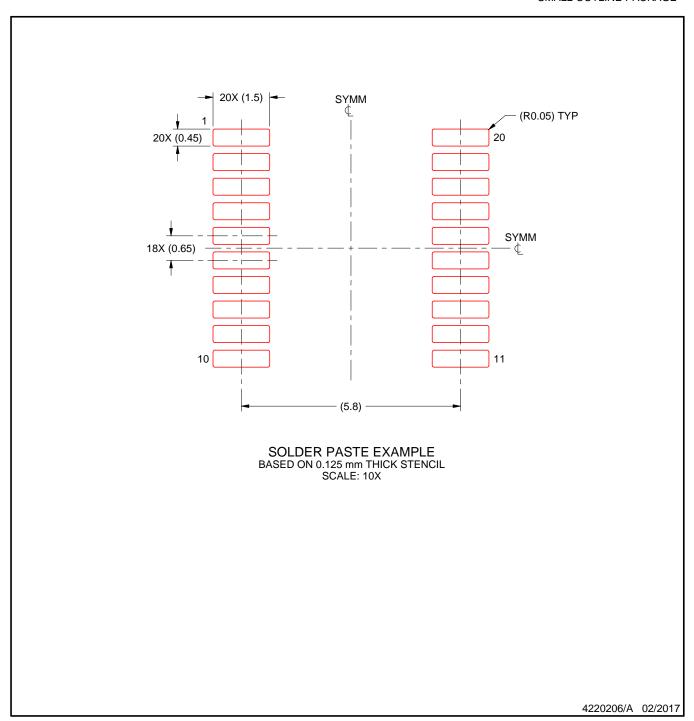
NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



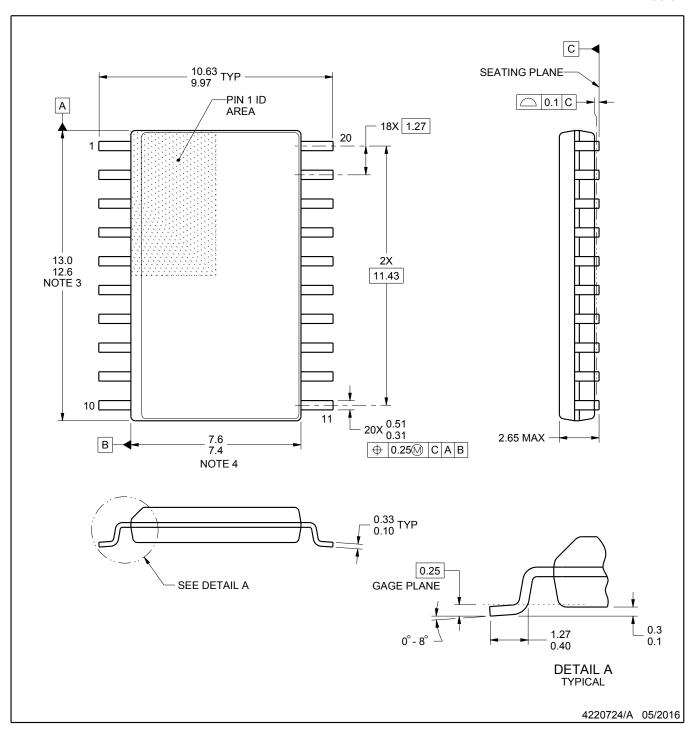
NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.





SOIC



## NOTES:

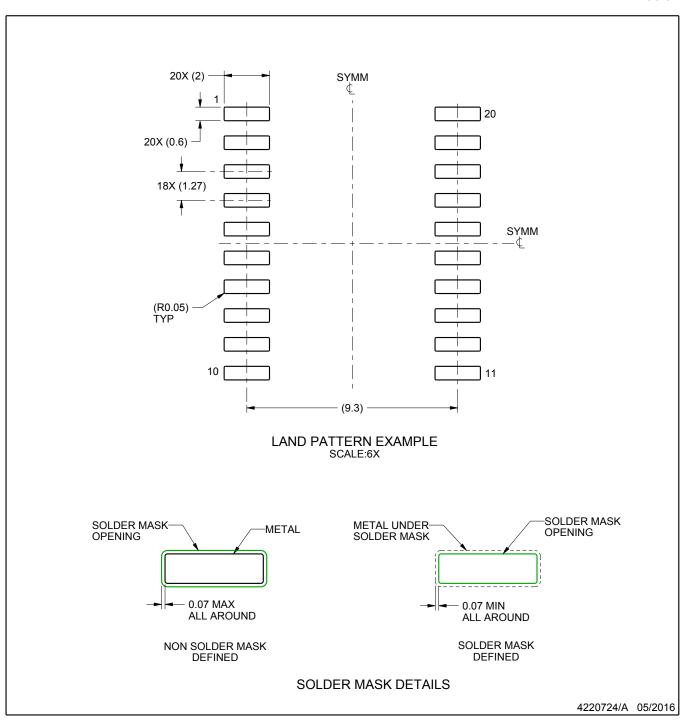
- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

  2. This drawing is subject to change without notice.

  3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
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- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm per side.
- 5. Reference JEDEC registration MS-013.



SOIC



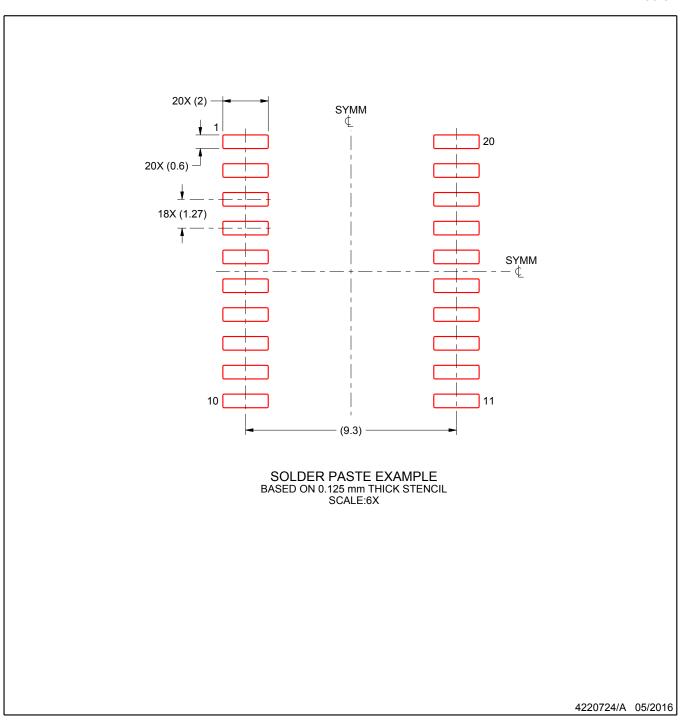
NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

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SOIC



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



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